Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/693,567	CIAVARELLA ET AL.
Examiner	Art Unit

3754

PHILIPPE S. DERAKSHANI

	SFAR	CHED				
SEARCHED						
Class	Subclass	Date	Examiner			
222	321.9 325 181.3	8/3/2005	PD			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
222=321.9, x= 222/325		
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